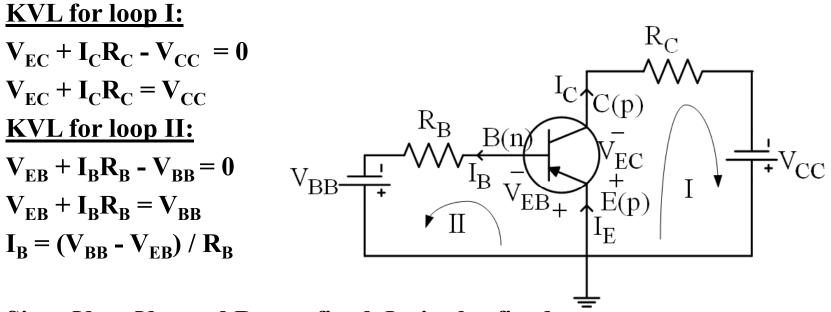
CLASS 21&22

STABILITY OF BJT BIASING CIRCUITS, BJT AS A SWITCH, SMALL-SIGNAL EQUIVALENT CIRCUIT OF THE BJT AND FETs

STABILITY OF THE BIASING CIRCUITS



Since V_{BB} , V_{EB} and R_B are fixed, I_B is also fixed.

If $T\uparrow$, $I_C\uparrow$; hence, $V_{EC}\downarrow$. The Q point will change as the Q point of the CE circuit is I_{CQ} and V_{ECQ} .

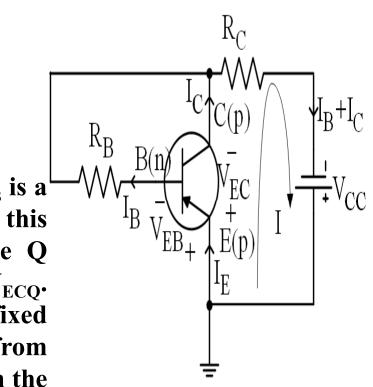
As the I_B is fixed, this condition does not help in stabilizing the Q point of the circuit when changes occur. Thus, fixed-current biasing circuit is said to be less stable in terms of its biasing performance.

KVL of loop I:

 $V_{EC} + (I_B + I_C)R_C = V_{CC}$ (1) <u>KVL of loop II:</u>

 $\mathbf{I}_{\mathbf{B}} = (\mathbf{V}_{\mathbf{EC}} - \mathbf{V}_{\mathbf{EB}}) / \mathbf{R}_{\mathbf{B}}$ (2)

From $I_C = \beta_{DC} I_B + I_{CEO}$, T \uparrow then $I_C \uparrow$ if I_B is a fixed current. From (1), $V_{EC}\downarrow$ when $I_{C}\uparrow$. If this happens, the Q point will change as the Q point of the CE circuit is I_{CO} and V_{ECO} . However, from (2), since V_{EB} and R_B are fixed values, I_B will \downarrow when $V_{EC} \downarrow$. Again, from $I_C = \beta_{DC} I_B + I_{CEO}$, when $T \uparrow I_{CEO} \uparrow$ but from the above, I_B will \downarrow . Hence, I_C will be maintained. This condition will also maintain the $(I_B+I_C)R_C$ term in (1). Hence, V_{EC} will be maintained at the quiescent value before the temperature change. Thus, collector feedback biasing circuit is said to be more stable in terms of its biasing performance.

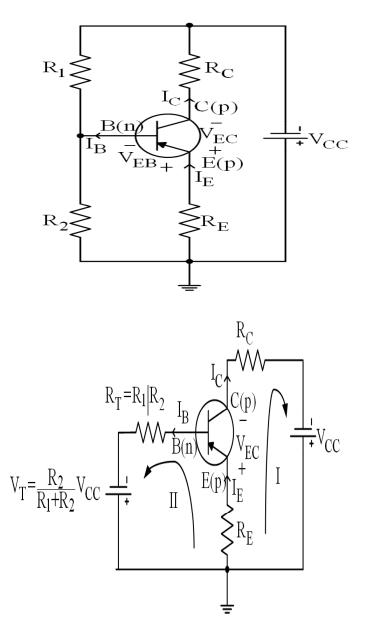


KVL of loop I:

 $I_E R_E + V_{EC} + I_C R_C = V_{CC}$ (1) KVL of loop II:

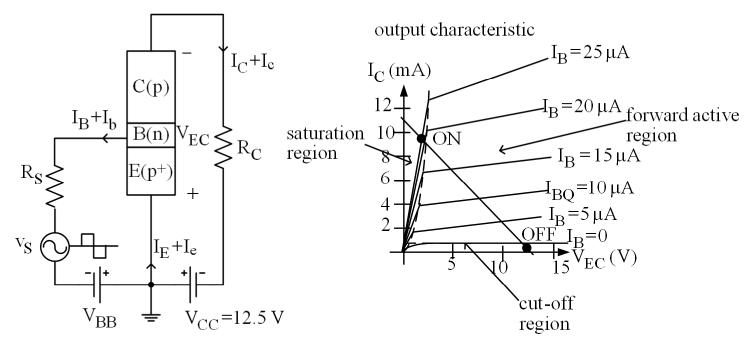
 $I_E R_E + V_{EB} + I_B R_T = V_T$ $I_E R_E + I_B R_T = V_T - V_{EB}$ (2)

When $T\uparrow$, then $I_C\uparrow$. I_E will also \uparrow as $I_C\approx \alpha I_E$. From (2), since V_{EB} , V_T , R_E and R_T are fixed values, when $I_E\uparrow$, then $I_B\downarrow$. From $I_C=\beta_{DC} I_B + I_{CEO}$, when $T\uparrow I_{CEO}\uparrow$ and will supposedly increase the I_C . However, this will make $I_B\downarrow$. Thus, I_C will be maintained. Therefore, I_B is helping to stabilize the circuit by maintaining the Q point. This circuit is the most popular amongst the 3 biasing circuits discussed.

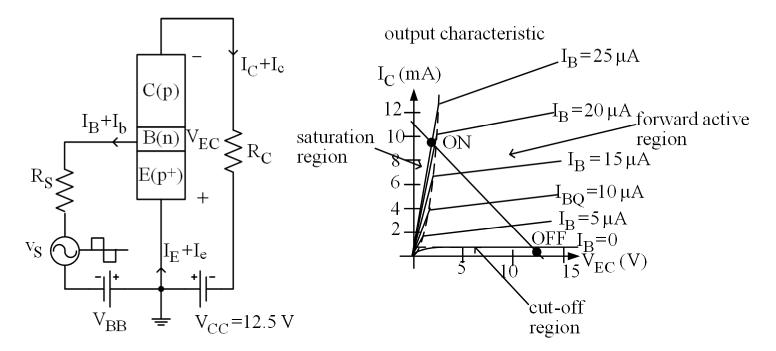


BJT AS A SWITCH

- In digital applications, the transistors are normally utilized as switches. As a switch, I_B is used to convert I_C from OFF to ON.
- OFF condition: high voltage and low current
- ON condition: low voltage and high current

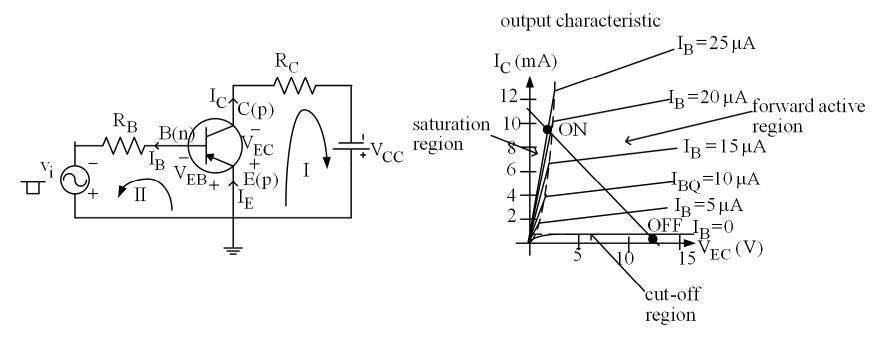


- Transistor is an o/c between E and C in the OFF condition.
- Transistor is a s/c between E and C in the ON condition.
- Hence, the transistor's operation is like a switch.



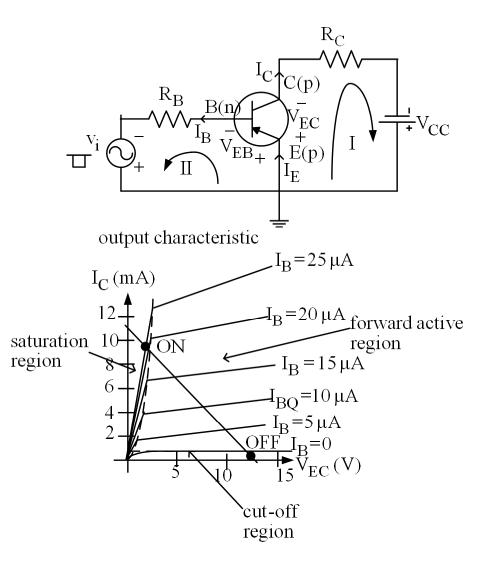
CUT-OFF

• If $|v_i|$ is < 0.7, the E-B junction will let only a very small insignificant current to flow. Under this condition, the E-B junction is still considered as OFF. $I_B = I_C = I_E \approx 0$. $V_{EC} = V_{CC}$. B-C junction is also rb. The transistor is said to be in the cut-off condition (voltage is high, current is very small).

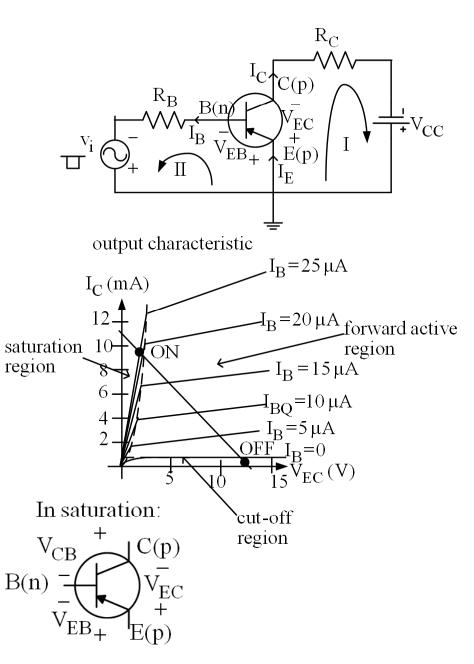


SATURATION

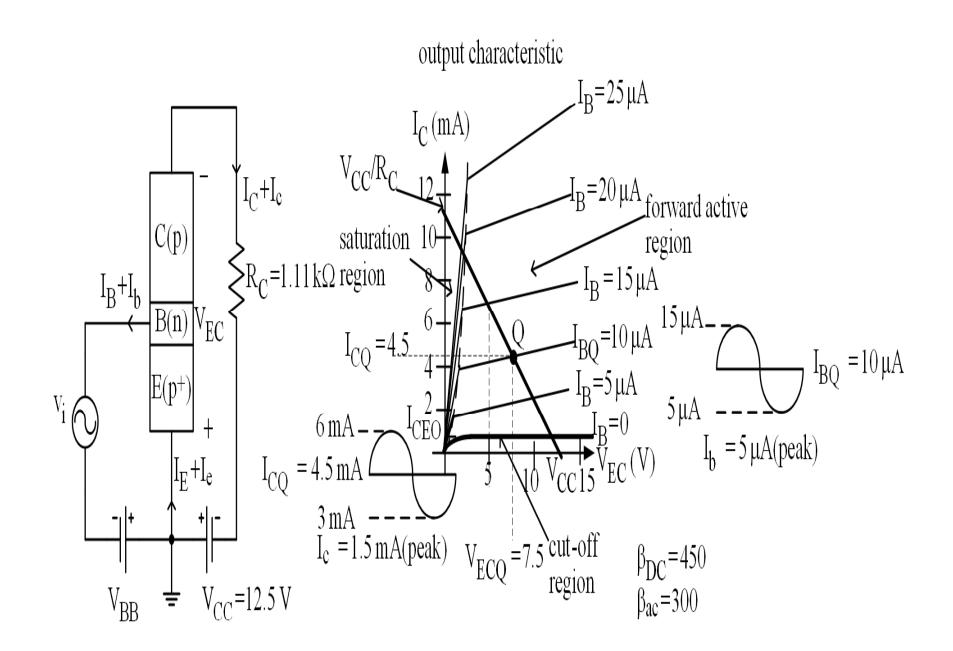
- If $|v_i| \uparrow$, $I_B \uparrow I_C \uparrow$ and $V_{EC} \downarrow$ (from $V_{EC} + I_C R_C = V_{CC}$). If the $|V_{EC}| < 0.7$ V, the device will enter the saturation region as both E-B and B-C junctions are fb.
- Under this condition, $|V_C| < |V_B|$. The B-C junction will be fb as the C is more +ve than the B. The B-C junction can be fb by a forward voltage of 0.4 to 0.5 V. The forward voltage drop of the B-C junction is smaller than the forward voltage drop of the E-B junction (i.e. 0.7 V) because C is doped less than E. $[V_o=(kT/q)ln(N_AN_D/n_i^2)].$



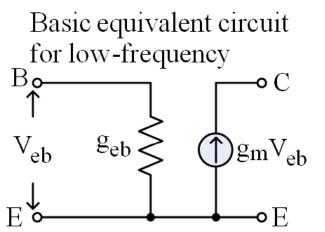
- This condition is called saturation as any increment in the I_B will only cause the I_C to increase by a small amount and therefore, V_{EC} will also decrease by a small amount.
- The minimum rb of the BC junction is when $V_{BC} = 0$.
- In the saturation region, $\Delta I_C / \Delta I_B \neq \beta_{DC}$.
- As the forward voltage drop of the B-C junction is in the range 0.4 V to 0.5 V, then
- $V_{EB} V_{CB} V_{EC} = 0$. Under this condition, $V_{EC} = V_{EC(sat)} = 0.3 V$ to 0.2 V.
- $\mathbf{V}_{CC} = \mathbf{V}_{EC(sat)} + \mathbf{I}_{C(sat)}\mathbf{R}_{C}$ $\mathbf{I}_{C(sat)} = [\mathbf{V}_{CC} - \mathbf{V}_{EC(sat)}]/\mathbf{R}_{C}$



- BJT has 4 modes of operation, i.e. forward active, saturation, cut-off and inverted. The mode of operation is dependent on the biasing condition of the BE and BC junctions.
- In analogue circuits, transistors normally operate in the active mode.
- In digital circuits, all 4 modes might be involved.
- So far, we had seen the static (or DC) characteristics of the BJT. Now we will learn about the AC characteristics of the BJT when a small-signal voltage or current is superimposed on its DC signal. Small-signal means the peak AC voltage and current are smaller than their DC values.

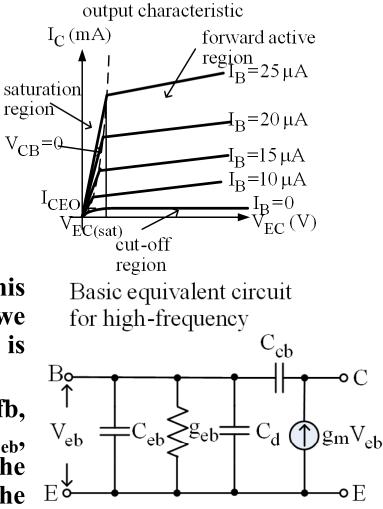


SMALL-SIGNAL EQUIVALENT CIRCUIT OF BJT



• $g_m = I_c/V_{eb}$ is the transconductance.

- $g_{eb} = I_b/V_{eb}$ is the i/p conductance. This conductance must be included as we are considering the current that is flowing through the fb E-B junction.
- At higher frequencies, when E-B is fb, there exist a depletion capacitance, C_{eb} , and diffusion capacitance, C_d . For the rb B-C junction, there exist only the depletion capacitance, C_{cb} .



Depletion capacitance:

Independent of whether the junction is forward or reverse biased, there exist the depletion region both sides of the on junction. The p-depletion region-n is similar structure to the structure of the capacitor. Due to the depletion region, depletion capacitance, C_i, exist.

 $C_j=dQ/dV=dQ/(WdQ/\epsilon A)=\epsilon A/W$ (unit for C_j is F/cm²)

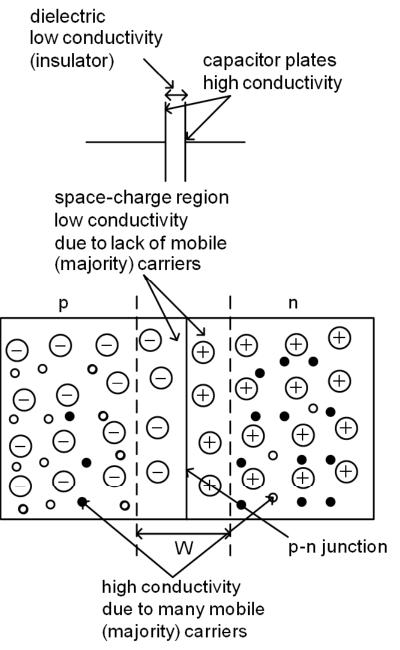
dQ = change of charge per unit area of the depletion layer.

dV = change of voltage applied.

A = cross-section area.

ε = permittivity of Si

W = width of the depletion region

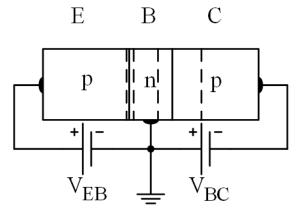


Diffusion capacitance

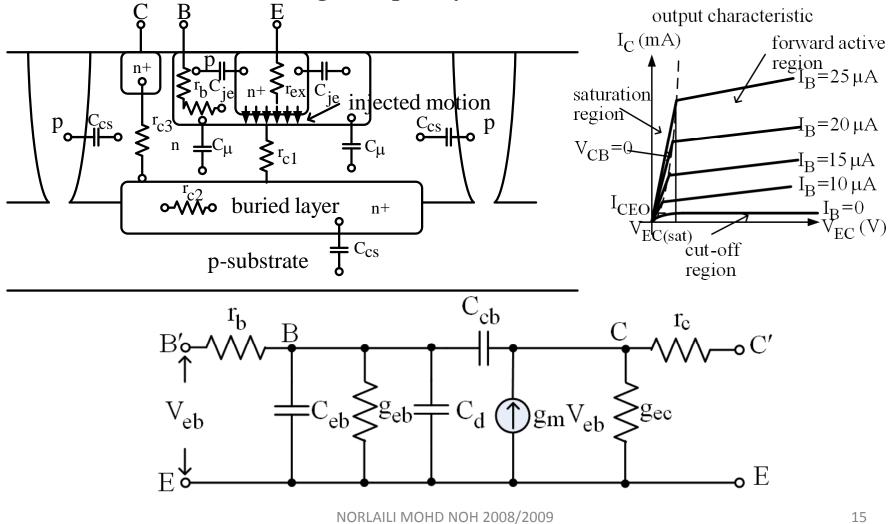
- When the p-n junction is fb, large current flows through the junction. This will result in many mobile carriers to be in the neutral B. The change in the mobile carriers corresponding to the change in the biasing voltage will result in the diffusion capacitance, C_d .
- $C_d = (Aq^2L_pp_{no}/kT)e^{qV/(kT)}$ where

 L_p = diffusion length of hole in the n material

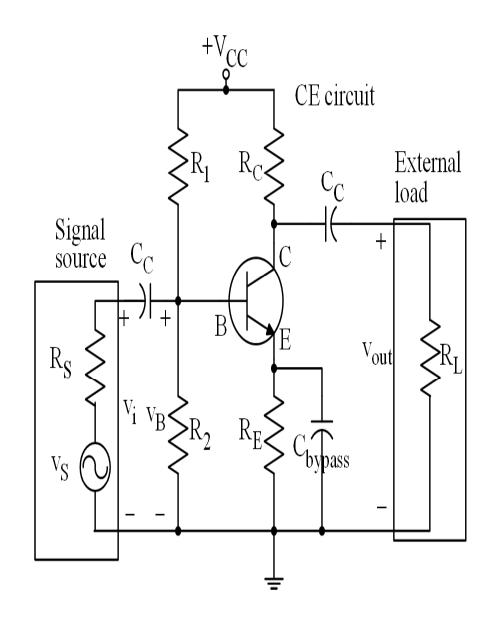
 p_{no} = equilibrium hole density in the n

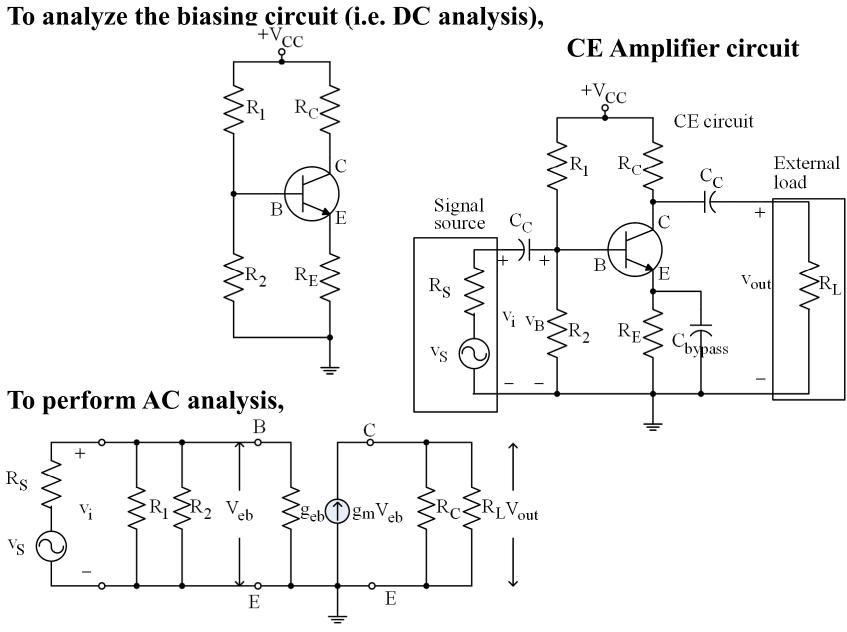


- If the Early Effect (or base width modulation effect) is to be considered, the output conductance, $g_{ec} = I_c/V_{ce}$, has to be included.
- If the resistance of the B and C are to be included, the equivalent circuit of the BJT at high-frequency becomes:



- C_C is a coupling capacitor. It limits the DC signal to the transistor and the biasing circuit only. The DC signal cannot reach the signal source and the external load as capacitor to a DC is an open circuit [X_C = 1/(2 π fC)].
- C_{bypass} is a bypass capacitor. It takes out R_E (the emitter resistor that can reduce the amplifier's gain) from the AC signal's path but let R_E plays its part in stabilizing the biasing of the transistor. To the AC signal, the capacitor is a short circuit.





Field Effect Transistors (FET) and Bipolar Junction Transistors (BJT) Differences

	BJT	FET
1.	Bipolar device	Unipolar device
	Both current carriers (electrons	One current carrier (majority
	and holes) contribute to the	carrier) influences the current
	current flow.	flow.
2.	Current controlled device	Voltage controlled device
	Base current (I _B) controls	Gate to Source voltage (V _{GS})
	Collector current (I _C).	controls the amount of current
		(I _D) flowing.
3.	<u>Z_i of BJTs < Z_i of FETs</u>	High input impedance
	Depending on the configuration:	$Z_i =$ hundreds of M Ω .
	CE - A_V is high, Z_i is quite high.	
	CC - A_V is 1, Z_i is high.	
	$CB - A_V$ is high, Z_i is low.	
4.	Not as stable as the FET towards	More <u>stable</u> towards temperature
	temperature variation.	variation.
5.	Larger and more complex than	Smaller in size and easier to
	FET.	fabricate as compared to the BJT.

Due to 4 and 5, FET can be found in many digital ICs.

FIELD EFFECT TRANSISTORS

- 1. Junction Field Effect Transistor (JFET)
- 2. Metal-Oxide-Semiconductor Field Effect Transistor (MOSFET)

Generally known as:

- 1. Metal-Insulator-Semiconductor FET (MISFET) where the insulator may not be silicon dioxide (SiO₂) and semiconductor may not be Silicon (Si).
- 2. Insulated Gate FET (IGFET) symbolizing the device which Gate is insulated from the Body by the SiO₂.

The insulated Gate from Body causes the gate current (I_G) to be considered as 0 in many analysis and calculation. In reality, this current is in the femto (10⁻¹⁵A) range.

Differences between JFET and MOSFET

- The Gate of the MOSFET is insulated from the channel (and Body) by a layer of SiO₂.
- MOSFET does not have a p-n junction that controls the width of the channel and consequently the current.

MOSFET Application

- In Very-Large-Scale-Integrated (VLSI) circuits. Examples: microprocessor and memory chips.
- At present, even the RF analog integrated circuits are implementing MOSFETs as these devices have smaller dimensions and cheaper to fabricate.

To summarize, the MOSFETs are typically used in IC design.

Types of MOSFET

- Depletion-enhancement (typically known as DE-MOSFET)
- Enhancement-only MOSFET (typically known as E-MOSFET)